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File 275:Gale Group Computer DB(TM) 1983-2006/Aug 29
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File 621:Gale Group New Prod.Annou.(R) 1985-2006/Aug 30
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File 636:Gale Group Newsletter DB(TM) 1987-2006/Aug 29
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File 16:Gale Group PROMT(R) 1990-2006/Aug 29
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File 160:Gale Group PROMT(R) 1972-1989
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File 148:Gale Group Trade & Industry DB 1976-2006/Aug 30
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File 624:McGraw-Hill Publications 1985-2006/Aug 29
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File 15:ABI/Inform(R) 1971-2006/Aug 29
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File 647:cmp Computer Fulltext 1988-2006/Oct w2
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File 674:Computer News Fulltext 1989-2006/Aug w2
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File 696:DIALOG Telecom. Newsletters 1995-2006/Aug 29
(c) 2006 Dialog
File 369:New Scientist 1994-2006/Jul w4
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Set	Items	Description
S1	43744	"TEST"() (VECTOR? ? OR PATTERN? ? OR BIT? ? OR BYTE? ? OR SEQUENCE? ? OR SERIES OR STRING? ? OR DATA OR INFORMATION OR SIGNAL? ? OR CHARACTER? ? OR INPUT? ? OR SEGMENT? ?)
S2	242	SCAN(1W)VECTOR? ?
S3	1169148	CHIP OR MICROCHIP OR IC OR INTEGRATED()CIRCUIT OR ASIC OR - PCB OR SOC
S4	32911	(SECOND? OR 2ND OR ANOTHER OR OTHER OR DIFFERENT OR SEPARATE OR ADJACENT OR NEIGHBOR? OR RECEIVER OR TARGET OR DESTINATION) (2W)S3
S5	11966100	ERROR? ? OR FAULT?? OR FLAW? ? OR FAIL? OR PROBLEM? ? OR ANOMAL? OR IMPROPER? OR DEFECT? OR GLITCH?? OR BAD OR DISTORT? OR IRREGULARIT? OR INACCURA? OR ABNORMAL? OR INCORRECT? OR GOOD OR CORRECT?? OR PROPER?
S6	1537459	S5(10N)(DETERMIN? OR TEST??? OR CHECK??? OR ANALYZ? OR ANALYS? OR ASSESS? OR IDENTIFY??? OR IDENTIFICATION OR IDENTIFIES OR IDENTIFIED OR CALCULAT? OR ASCERTAIN? OR FIND???? OR COMPUTE OR COMPUTES OR COMPUTED OR COMPUTING)
S7	947776	S5(10N)(GAUG? OR EVALUAT? OR MEASUR? OR DISCERN? OR EXAMIN? OR JUDG??? OR DECID??? OR DETECT??? OR VERIF? OR DIAGNOS? OR INDICAT? OR DESIGNAT? OR SPECIFY??? OR SPECIFIE? ?)
S8	37	S1:S2(20N)S4
S9	19	S8(100N)S6:S7
S10	12	RD (unique items)

File 347:JAPIO Dec 1976-2005/Dec(Updated 060404)

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File 350:Derwent WPIX 1963-2006/UD=200654

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Set	Items	Description
S1	36679	"TEST"() (VECTOR? ? OR PATTERN? ? OR BIT? ? OR BYTE? ? OR SEQUENCE? ? OR SERIES OR STRING? ? OR DATA OR INFORMATION OR SIGNAL? ? OR CHARACTER? ? OR INPUT? ? OR SEGMENT? ?)
S2	60	SCAN(1W)VECTOR? ?
S3	722618	CHIP OR MICROCHIP OR IC OR INTEGRATED()CIRCUIT OR ASIC OR PCB OR SOC
S4	13005	(SECOND? OR 2ND OR ANOTHER OR OTHER OR DIFFERENT OR SEPARATE OR ADJACENT OR NEIGHBOR? OR RECEIVER OR TARGET OR DESTINATION) (2W) S3
S5	6292563	ERROR? ? OR FAULT?? OR FLAW? ? OR FAIL? OR PROBLEM? ? OR ANOMAL? OR IMPROPER? OR DEFECT? OR GLITCH?? OR BAD OR DISTORT? OR IRREGULARIT? OR INACCURA? OR ABNORMAL? OR INCORRECT? OR GOOD OR CORRECT?? OR PROPER?
S6	317246	S5(10N) (DETERMIN? OR TEST??? OR CHECK??? OR ANALYZ? OR ANALYS? OR ASSESS? OR IDENTIFY??? OR IDENTIFICATION OR IDENTIFIES OR IDENTIFIED OR CALCULAT? OR ASCERTAIN? OR FIND??? OR COMPUTE OR COMPUTES OR COMPUTED OR COMPUTING)
S7	648372	S5(10N) (GAUG? OR EVALUAT? OR MEASUR? OR DISCERN? OR EXAMIN? OR JUDG??? OR DECID??? OR DETECT??? OR VERIF? OR DIAGNOS? OR INDICAT? OR DESIGNAT? OR SPECIFY??? OR SPECIFIE? ?)
S8	69	S1:S2(20N) S4
S9	19	S8 AND S6:S7
S10	9	S9 AND AC=US/PR AND AY=(1963:2002)/PR
S11	15	S9 AND AC=US AND AY=1963:2002
S12	15	S9 AND AC=US AND AY=(1963:2002)/PR
S13	10	S9 AND PY=1963:2002
S14	16	S10:S13

File 348:EUROPEAN PATENTS 1978-2006/ 200634

(c) 2006 European Patent Office

File 349:PCT FULLTEXT 1979-2006/UB=20060824UT=20060817

(c)

Set	Items	Description
S1	28808	"TEST"() (VECTOR? ? OR PATTERN? ? OR BIT? ? OR BYTE? ? OR SEQUENCE? ? OR SERIES OR STRING? ? OR DATA OR INFORMATION OR SIGNAL? ? OR CHARACTER? ? OR INPUT? ? OR SEGMENT? ?)
S2	126	SCAN(1W)VECTOR? ?
S3	393488	CHIP OR MICROCHIP OR IC OR INTEGRATED()CIRCUIT OR ASIC OR PCB OR SOC
S4	19659	(SECOND OR SECONDARY OR 2ND OR ANOTHER OR OTHER OR DIFFERENT OR SEPARATE OR ADJACENT OR NEIGHBOR? OR RECEIVER OR TARGET OR DESTINATION)(2W)S3
S5	1602408	ERROR? ? OR FAULT?? OR FLAW? ? OR FAIL? OR PROBLEM? ? OR ANOMAL? OR IMPROPER? OR DEFECT? OR GLITCH?? OR BAD OR DISTORT? OR IRREGULARIT? OR INACCURA? OR ABNORMAL? OR INCORRECT? OR GOOD OR CORRECT?? OR PROPER?
S6	379191	S5(10N)(DETERMIN? OR TEST??? OR CHECK??? OR ANALYZ? OR ANALYS? OR ASSESS? OR IDENTIFY??? OR IDENTIFICATION OR IDENTIFIES OR IDENTIFIED OR CALCULAT? OR ASCERTAIN? OR FIND??? OR COMPUTE OR COMPUTES OR COMPUTED OR COMPUTING)
S7	390752	S5(10N)(GAUG? OR EVALUAT? OR MEASUR? OR DISCERN? OR EXAMIN? OR JUDG??? OR DECID??? OR DETECT??? OR VERIF? OR DIAGNOS? OR INDICAT? OR DESIGNAT? OR SPECIFY??? OR SPECIFIE? ?)
S8	115	S1:S2(20N)S4
S9	45	S8(100N)S6:S7
S10	366	S4(20N)S6:S7
S11	21	S8(100N)S10
S12	10	S11 AND AC=US/PR AND AY=(1978:2002)/PR
S13	10	S11 AND AC=US AND AY=1978:2002
S14	10	S11 AND AC=US AND AY=(1978:2002)/PR
S15	12	S11 AND PY=1978:2002
S16	17	S12:S15
S17	17	IDPAT (sorted in duplicate/non-duplicate order)

File 8:Ei Compendex(R) 1970-2006/Aug w3
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 File 56:Computer and Information Systems Abstracts 1966-2006/Aug
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 File 60:ANTE: Abstracts in New Tech & Engineer 1966-2006/Aug
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Set	Items	Description
S1	108621	"TEST"() (VECTOR? ? OR PATTERN? ? OR BIT? ? OR BYTE? ? OR SEQUENCE? ? OR SERIES OR STRING? ? OR DATA OR INFORMATION OR SIGNAL? ? OR CHARACTER? ? OR INPUT? ? OR SEGMENT? ?)
S2	176	SCAN(1W)VECTOR? ?
S3	817717	CHIP OR MICROCHIP OR IC OR INTEGRATED()CIRCUIT OR ASIC OR PCB OR SOC
S4	7316	(SECOND? OR 2ND OR ANOTHER OR OTHER OR DIFFERENT OR SEPARATE OR ADJACENT OR NEIGHBOR? OR RECEIVER OR TARGET OR DESTINATION)(2W)S3
S5	17071040	ERROR? ? OR FAULT?? OR FLAW? ? OR FAIL? OR PROBLEM? ? OR ANOMAL? OR IMPROPER? OR DEFECT? OR GLITCH?? OR BAD OR DISTORT? OR IRREGULARIT? OR INACCURA? OR ABNORMAL? OR INCORRECT? OR GOOD OR CORRECT?? OR PROPER?
S6	3205661	S5(10N)(DETERMIN? OR TEST??? OR CHECK??? OR ANALYZ? OR ANALYS? OR ASSESS? OR IDENTIFY??? OR IDENTIFICATION OR IDENTIFIES OR IDENTIFIED OR CALCULAT? OR ASCERTAIN? OR FIND???? OR COMPUTE OR COMPUTES OR COMPUTED OR COMPUTING)
S7	2366280	S5(10N)(GAUG? OR EVALUAT? OR MEASUR? OR DISCERN? OR EXAMIN? OR JUDG??? OR DECID??? OR DETECT??? OR VERIF? OR DIAGNOS? OR INDICAT? OR DESIGNAT? OR SPECIFY??? OR SPECIFIE? ?)
S8	27	S1:S2(20N)S4
S9	6	S8 AND S6:S7
S10	4	RD (unique items)